

Search Notes	Application/Control No.	Applicant(s)/Patent Under Reexamination
	10765383	LAI ET AL.
	Examiner	Art Unit
	Debelie, Mitiku	2621

SEARCHED

Class	Subclass	Date	Examiner
386	46	8/8/2007	MD
358	1.9	8/8/2007	MD
711	100	8/8/2007	MD
395	843, 600	8/8/2007	MD
369	47.38	8/8/2007	MD
375	240.03	8/8/2007	MD

SEARCH NOTES

Search Notes	Date	Examiner

INTERFERENCE SEARCH

Class	Subclass	Date	Examiner